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thin solid films

Contents

Preface ix

Sponsors x

X-Ray analysis of strain in thin films

Strain analysis by X-ray diffraction
P.F. Fewster and N.L. Andrew 1

Limits of validity of the crystallite group method in stress determination of thin film structures
P. Gergaud, S. Labat and O. Thomas 9

New X-ray diffraction method for materials science
Z. Swiatek, J.T. Bonarski, R. Ciach and Z.T. Kuznicki 16

Combined high resolution X-ray diffraction and EXAFS studies of $Si_{(1-x)}Ge_x$ heterostructures
P. De Padova, R. Felici, R. Larciprete, L. Ferrari, L. Ortega, V. Formoso, F. Comin and A. Balerna 20

HR XRD for the analysis of ultrathin centrosymmetric strained DB-RTD heterostructures
M. Haase, W. Prost, P. Velling, Q. Liu and F.J. Tegude 25

HRXRD study of compositional uniformity of MOVPE grown InGaAs
J. Xu and X.J. Cheng 29

Fine interference effects in X-ray diffraction from multilayered structures
E. Zolotoyabko 35

Investigation of inhomogeneous structures of near-surface-layers in ion-implanted silicon
Z. Swiatek, J.T. Bonarski, R. Ciach, Z.T. Kuznicki, I.M. Fodchuk, M.D. Raransky and P. Gorley 39

Ion-assisted deposition of Ag(001)/Fe(001) multilayers: interface roughness
G. Gladyszewski, C. Jaouen, A. Declemy, J.C. Girard and P. Guerin 44

X-Ray analysis of crystalline structure

X-ray scattering study of quantum wires and lateral periodic heterostructures
L. Tapfer, L. De Caro, Y. Zhuang, P. Sciacovelli and A. Sacchetti 49

Study of structural properties of MOVPE grown ZnMgSSe layer by HRXRD and cathodoluminescence
J. Xu, Q. Liu, H. Kalisch, J. Woitok, M. Heuken and H. Lakner 57

In-depth structural X-ray investigation of PECVD grown diamond films on titanium alloys
P. Andreazza, M.I. De Barros, C. Andreazza-Vignolle, D. Rats and L. Vandenbulcke 62

Combined characterization of conductive materials by infrared spectroscopic ellipsometry and grazing X-ray reflectance
P. Boher, M. Luttmann, J.L. Stehle and L. Hennet 67

X-ray reflectivity of multilayer mirrors for the water window
H. Grimmer, P. Böni, U. Breitmeier, D. Clemens, M. Horisberger, H.-.C. Mertins and F. Schäfers 73

Structure characterization of metallic multilayers by symmetric and asymmetric X-ray diffraction
G. Gladyszewski, S. Labat, P. Gergaud and O. Thomas 78

Morphological study of cobalt aggregates in magnetic multilayers by grazing-incidence small-angle X-ray scattering
A. Naudon, D. Babonneau, F. Petroff and A. Vaurès 81

Lattice parameter change in submicron Si whiskers
A.I. Klimovskaya, I.P. Ostrovskii, S.V. Fadeyev, M.S. Fruginskii and I.O. Rudyi 84

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TEM analysis of crystalline structure

Atomic and electronic structure of diamond grain boundaries analyzed by HRTEM and EELS
H. Ichinose and M. Nakanose 87

Application of focused ion beam milling to cross-sectional TEM specimen preparation of industrial materials including heterointerfaces
K. Kuroda, M. Takahashi, T. Kato, H. Saka and S. Tsuji 92

EELS analysis of hydrogenated diamond-like carbon films
L. Ponsonnet, C. Donnet, K. Varlot, J.M. Martin, A. Grill and V. Patel 97

TEM observation of structural differences between two types of Ni silicide/Si thin films caused by FIB irradiation
M. Tanaka, K. Furuya and T. Saito 101

Transmission electron microscopy of thin-film transistors on glass substrates
K. Tsujimoto, S. Tsuji, K. Kuroda and H. Saka 106

Surface observation of Mo nanocrystals deposited on Si (111) thin films by a newly developed ultrahigh vacuum field-emission transmission electron microscope
M. Tanaka, K. Furuya, M. Takeguchi and T. Honda 110

Growth structure of nickel films on GaAs(001) by d.c.-biased plasma-sputter-deposition
J. Yang, K. Makihara, H. Nakai, M. Hashimoto, A. Barna and P.B. Barna 115

TEM observations of nanometer thick cobalt deposits in alumina sandwiches
F. Fettar, J.-L. Maurice, F. Petroff, L.F. Schelp, A. Vaurès and A. Fert 120

Stable and metastable phases in the vacuum arc deposited Co thin films
B.B. Straumal, W. Gust, N.F. Vershinin, T. Watanabe, Y. Igarashi and X. Zhao 124

Electrode-width dependence of resistivity and structure of aluminum electrode thin film electron beam evaporated on lithium tantalate
K. Noguchi, H. Nakai, H. Ohashi and M. Hashimoto 128

Cross-sectional TEM observation of multilayer structure of a galvannealed steel
T. Kato, M.H. Hong, K. Nunome, K. Sasaki, K. Kuroda and H. Saka 132

Nanocrystalline thin titanium films grown on potassium bromide single crystals
T. Braisaz, P. Ruterana, G. Nouet, Ph. Komninou, Th. Kehagias, Th. Karakostas, P. Poulopoulos, M. Aggelakeris, N. Flevaris and A. Serra 140

Transmission electron microscopy investigation of the structural characteristics of amorphous tetrahedral carbon films
Ch.B. Lioutas, N. Vouroutzis, S. Logothetidis and H. Lefakis 144

Image processing and HREM

HREM: ultimate performances
D. Van Dyck 148

The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE
P. Vermaut, A. Béré, P. Ruterana, G. Nouet, A. Hairie and E. Paumier 153

Quantitative analysis of strain field in thin films from HRTEM micrographs
E. Snoeck, B. Warot, H. Ardhuin, A. Rocher, M.J. Casanove, R. Kilaas and M.J. Hÿtch 157

Microstructure imaging of the YBCO thin film/MgO substrate interface: HRTEM and Fourier analysis of the Moiré fringe pattern
S. Auzary, F. Pailloux, M.F. Denanot and R.J. Gaboriaud 163

HRTEM study of strained Si/Ge multilayers
M. Romeo, C. Uhlaq-Bouillet, J.P. Deville, J. Werckmann, G. Ehret, R. Chelly, D. Dentel, T. Angot and J.L. Bischoff 168

Studies of metamorphic III–V heterostructures by digital processing of HREM images
A. Rocher and E. Snoeck 172

Optical and digital processing of H.R.T.E.M. images of Si thin films deposited by R.T.C.V.D.
F. Pailloux, E.L. Mathé, H. Garem, R.J. Gaboriaud, R. Monna and J.C. Muller 177

Combined TEM and X-Ray of thin films analysis

Structural aspects of the interface in Silicon-on-sapphire system
E. Gartstein, S. Lach and D. Mogilyanski 182

Determination of interfacial roughness and its correlation in sputtered CoZr/Cu multilayers
J. Langer, R. Mattheis, J. Kräußlich, St.. Senz, D. Hesse, Th. Schuhrke and J. Zweck 187

Investigation of chemical ordering in MBE-grown Co_xPt_{1-x} films by X-ray diffraction and high-resolution transmission electron microscopy
M. Maret, C. Ulhaq-Bouillet, W. Staiger, M.C. Cadeville, S. Lefebvre and M. Bessière 191

XRD and TEM study of heteroepitaxial growth of zirconia on magnesia single crystal
R. Guinebretière, B. Soulestin and A. Dauger 197

Epitaxial growth of $YBa_2Cu_3O_{7-x}$ thin films on (111) $SrTiO_3$ substrates
E. Brecht, J. Reiner, M. Rodewald and G. Linker 202

Crystallisation of perovskite PZT films on MgO substrates
G. Barucca, A. De Benedittis, A. Di Cristoforo, G. Majni, P. Mengucci, F. Leccabue and B.E. Watts 207

Microstructure and strain relaxation in $YBa_2Cu_3O_7$ epitaxial thin films
J.-L. Maurice, O. Durand, M. Drouet and J.-P. Contour 211

Structural properties of $Bi_2Sr_2CaCu_2O_{8+\delta}$ thin films on (110) oriented $SrTiO_3$ substrates
E. Brecht, C. Træholt, R. Schneider, J. Geerk, O. Meyer and G. Linker 215

Author Index of Volume 319 219

Subject Index of Volume 319 220

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